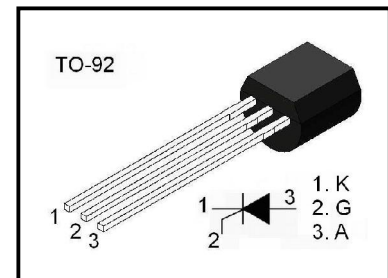


Silicon Controlled Rectifiers

PNPN devices designed for high volume, linepowered consumer applications such as relay and lamp drivers, small motor controls, gate drivers for larger thyristors, and sensing and detection circuits. Supplied in an inexpensive plastic TO-92 package which is readily adaptable for use in automatic insertion equipment.

Features

- Sensitive Gate Allows Triggering by Microcontrollers and Other Logic Circuits
- Blocking Voltage to 600 V
- On-State Current Rating of 0.8 A RMS at 80°C
- High Surge Current Capability -10 A
- Minimum and Maximum Values of I_{GT} , V_{GT} and I_H Specified for Ease of Design



Absolute Maximum Ratings (Ta=25°C)

Parameter	Symbol	Value	Unit
Peak Repetitive Forward Voltage	V_{DRM}	600	V
Reverse Blocking Voltage	V_{RRM}	600	V
On-State Current	$I_{T(RMS)}$	0.8	A
Peak Forward Surge Current	I_{TSM}	10	A
Circuit Fusing Consideration, (t = 8.3 ms)	I^2t	0.415	A ² s
Peak Reverse Gate Voltage	V_{GRM}	5.0	V
Peak Gate Current	I_{GM}	1.0	A
Gate Dissipation	$P_{G(AV)}$	0.1	W
Operating Junction Temperature	T_j	-40~+110	°C
Storage Temperature	T_{stg}	-40~+150	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. V_{DRM} for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.

2. See ordering information for exact device number options.

Thermal Characteristics

Parameter	Symbol	Max	Unit
Thermal Resistance, Junction-to-Case Junction-to-Ambient	$R_{\theta JC}$ $R_{\theta JA}$	75 200	$^{\circ}C/W$
Lead Solder Temperature ($<1/16''$ from case, 10 secs max)	T_L		$^{\circ}C$

Electrical Characteristics ($T_C=25^{\circ}C$, unless otherwise noted)

Parameter	Symbol	Conditions	Value		Unit
			Min	Max	
Peak Repetitive Off-State Voltage	V_{DRM} V_{RRM}		600		V
Peak Repetitive Forward or Reverse Blocking Current (Note 2)	I_{DRM} I_{RRM}	$T_C=25^{\circ}C$ $T_C=110^{\circ}C$		10 100	μA
On state voltage	V_{TM}	$I_T = 1A, T_A=25^{\circ}C$		1.7	V
Gate trigger current	I_{GT}	$V_{AK} = 7V, R_L=100\Omega$		200	μA
Holding current	I_H	$T_C= 25^{\circ}C$ $T_C= -40^{\circ}C$ $V_{AK} = 7V, I_H=20mA$		5 10	mA
Latch Current	I_L	$T_C= 25^{\circ}C$ $T_C= -40^{\circ}C$ $V_{AK} = 7V, I_G= 200\mu A$		10 15	mA
Gate trigger voltage	V_{GT}	$T_C= 25^{\circ}C$ $T_C= -40^{\circ}C$ $V_{AK} = 7V, R_L=100\Omega$		0.8 1.2	V
Critical Rate of Rise of Off-State Voltage	dV/dt	$V_D = \text{Rated } V_{DRM},$ Exponential Waveform, $R_{GK} = 1k\Omega$	10		$V/\mu s$
Critical Rate of Rise of On-State Current	di/dt	$I_{PK} = 20A, P_W=10\mu s$ $di_G/dt=1A/\mu s, I_{GT}=20mA$		50	$A/\mu s$

*Indicates Pulse Test: Pulse Width ≤ 1.0 ms, Duty Cycle $\leq 1\%$.

3. $R_{GK} = 1 k\Omega$ included in measurement.

4. Does not include R_{GK} in measurement.

Typical Characteristics

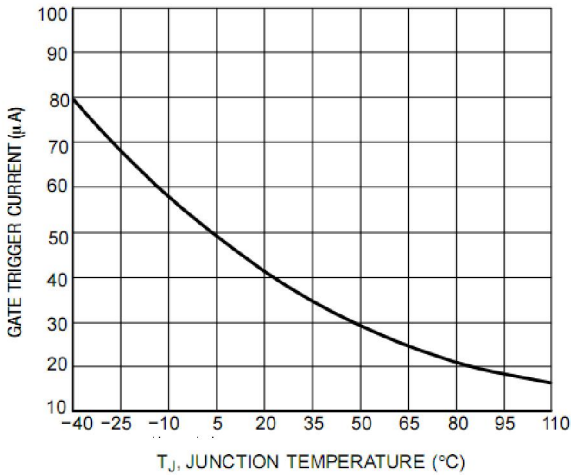


Figure 1. Typical Gate Trigger Current vs Junction Temperature

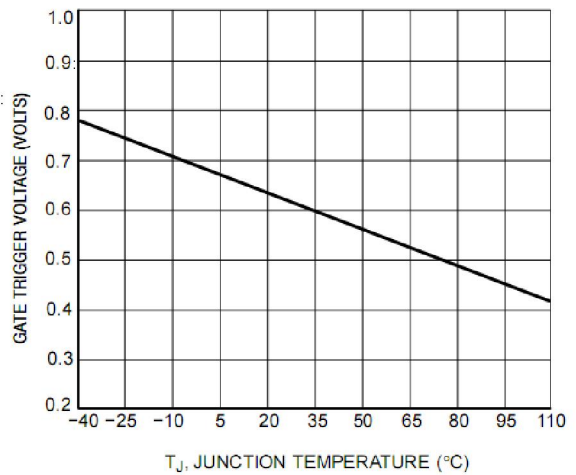


Figure 2. Typical Gate Trigger Voltage vs Junction Temperature

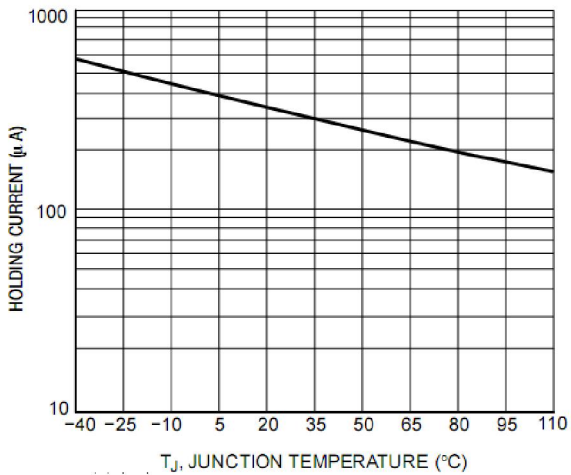


Figure 3. Typical Holding Current vs Junction Temperature

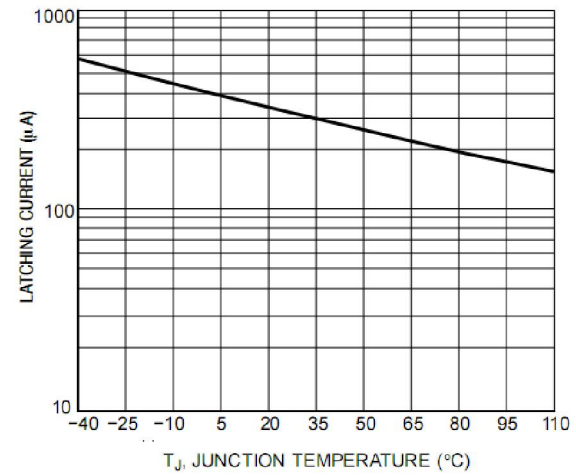


Figure 4. Typical Latching Current vs Junction Temperature

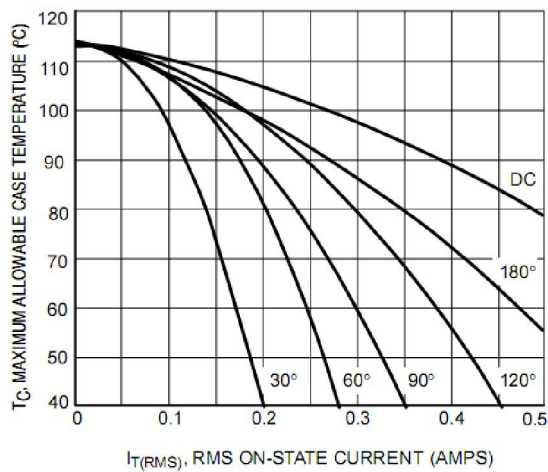


Figure 5. Typical RMS Current Derating

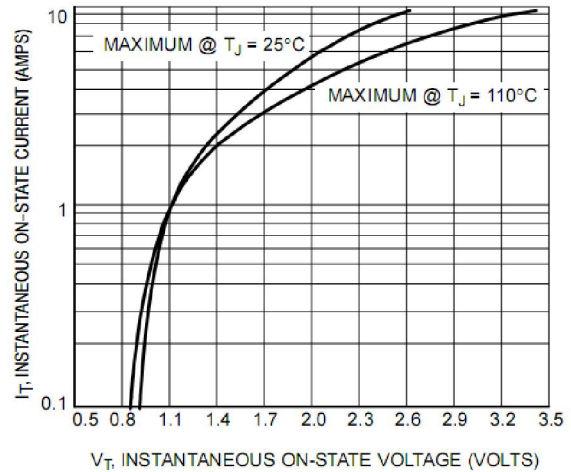


Figure 6. Typical On-State Characteristics

